





ISO 4287 - Roughness (S-L)			
F: None			
S-filter ( $\lambda_s$ ): None			
L-filter ( $\lambda_c$ ): Gaussian, 0.25 mm, Ends not cut			
Evaluation length: All $\lambda_c$ (1)			
Amplitude parameters			
Rp	0.7055	µm	
Rv	0.9368	µm	
Rz	1.642	µm	
Rc	0.8961	µm	No averaging (single value)
Rt	1.642	µm	
Ra	0.2915	µm	
Rq	0.3502	µm	
Rsk	-0.1235		
Rku	2.423		
Material ratio parameters			
Rmr	79.57	%	$c = 1 \mu\text{m}$ below highest peak
Rdc	0.6003	µm	$p = 20\%$ , $q = 80\%$
<b>Warnings</b>			
The workflow already contains a 'Metrological filter' operator.			

ISO 4287 - Roughness (S-L)			
F: None			
S-filter ( $\lambda_s$ ): None			
L-filter ( $\lambda_c$ ): Gaussian, 0.25 mm			
Evaluation length: All $\lambda_c$ (1)			
Amplitude parameters			
Rp	0.5310	µm	
Rv	0.9112	µm	
Rz	1.442	µm	
Rc	0.4701	µm	No averaging (single value)
Rt	1.442	µm	
Ra	0.1796	µm	
Rq	0.2306	µm	
Rsk	-0.9618		
Rku	4.208		
Material ratio parameters			
Rmr	96.40	%	$c = 1 \mu\text{m}$ below highest peak
Rdc	0.3621	µm	$p = 20\%$ , $q = 80\%$
<b>Warnings</b>			
The workflow already contains a 'Metrological filter' operator.			

## ISO 25178 - Primary surface

F: [Workflow] Leveled (LS-plane)

F: Leveled (LS), Angle  $3.025e-07^\circ$ ,  $4.233e-06^\circ$

S-filter ( $\lambda_s$ ): Gaussian,  $0.8 \mu\text{m}$

### Height parameters

Sq	0.3971	$\mu\text{m}$
Ssk	-0.09499	
Sku	2.718	
Sp	1.263	$\mu\text{m}$
Sv	1.983	$\mu\text{m}$
Sz	3.246	$\mu\text{m}$
Sa	0.3225	$\mu\text{m}$

### Information

The studiable contains non-measured points. The results are calcula...



